

NOVELLUS

Chamber Conductance Modeling Using Transition Flow CFD and a Thermal Radiation Analogy to Free Molecular Flow

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Outline

- **Introduction**
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 - **Modeling Approaches**
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Background

Motivation

- **What motivates the interest in this semiconductor modeling application?**
 - **Vacuum system conductance calculations always in use**
 - **We would like to avoid having to use specialty or non-commercial software in industrial applications**
 - Many operating conditions need Monte Carlo methodologies
 - **If calculations can be made simpler, that is a plus**
 - However, we need to model complex 3D geometries
 - We would like to use one modeling approach for all vacuum operating conditions (continuum to free molecular) if possible
 - Getting away from Monte Carlo models will speed up model run times significantly





Background

Motivation

- **What motivates the interest in this as a semiconductor processing application?**
 - **The chambers examined in this work are used in high density plasma CVD (chemical vapor deposition)**
 - In general, when these chambers deposit dielectric films in STI (shallow trench isolation) applications, the ability to fill gaps is improved at lower pressures
 - If the chamber pressure can be lowered easily and inexpensively, this is a marketplace advantage
 - If a smaller, cheaper pump can achieve the target process condition, it reduces tool cost and increases reliability
 - **Models can demonstrate the relative performance of chamber designs based on conductance differentials**





Background

Modeling Approaches

- **The idea of using an analogy between radiation heat transfer and free molecular flow is not new**
 - **However, it appears as though it is not well known in the semiconductor industry**
 - Bellcomm Memorandum (1968) on the World Wide Web
 - Peterson (1986) from Lockheed Martin presented the idea with validation in an aerospace application
 - Gantry et. al. (2001) from BOC Edwards discussed the idea in a short AVS presentation
 - Two software packages for aerospace use (MOLFLUX and NEVADA) mention this application in marketing materials
 - **The work being discussed here was presented last month at the 50th AVS Symposium in Baltimore**





Background

Modeling Approaches

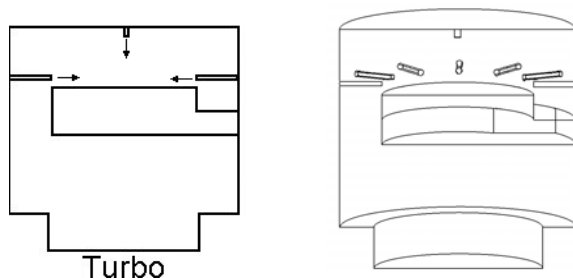
- **Near continuum transition flow is modeled here using Navier-Stokes CFD codes with slip BCs**
 - **Various transition flow models have been compared with pressure data from a Lam Research vacuum test cell**
 - Monte Carlo models
 - Shufflebotham, P. K., Bartel, T. J., Berney, B., *JVST B*, **13** (4) 1862 (1995)
 - CFD with no-slip BCs
 - Singh, V. Berney, B., Krishnan, A., *JVST A*, **14** (3) 1252 (1996)
 - CFD with slip BCs
 - Gochberg, L. A., Proceedings of the 23rd International Symposium on Rarefied Gas Dynamics, *Rarefied Gas Dynamics*, 1073 (2003)



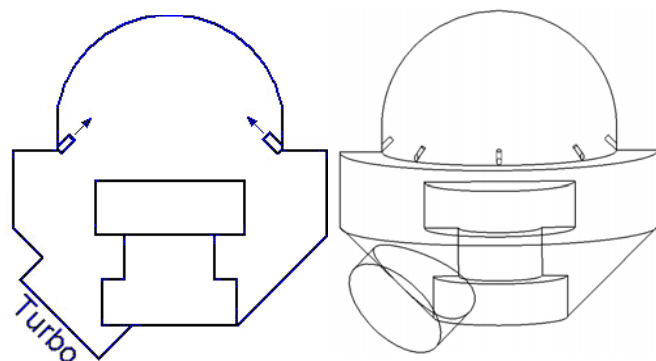
Models

3D Geometries

- **Two different 200-mm chambers were modeled**
 - **Look at the relative differences between chambers designed for STI applications**



**Centrally mounted turbopump
with cantilevered pedestal**



**200-mm SPEED™ with dual
turbopumps at 45° and a
centrally mounted pedestal**



Models

Transition Flow

- **Transition flow models done in commercial CFD software (CFD-ACE+)**
 - **Navier-Stokes continuum model at room temperature**
 - **Slip boundary conditions used to model flows at Knudsen numbers between 0.01 and 0.1**
 - **Inlet gas flows of 600 SCCM of argon with adiabatic chamber walls**
 - **Pumps initially modeled using constant pressure outlet boundaries consistent with 2200 l/s of total pumping**
 - The chamber with the 45 degree turbopumps uses two 1100 l/s pumps
 - The chamber with the single centrally mounted turbopump uses one 2200 l/s pump



Models

Free Molecular Flow

- Free molecular flow is modeled using a radiation heat transfer analogy ($P_{rad} \sim T^4$)
 - Models run in commercial Navier-Stokes software from Fluent and CFD-ACE+ using Discrete Ordinate Method

$$Q_{FM} = C (P_2 - P_1)$$

$$Q_{rad} = k_{rad} (T_2^4 - T_1^4) = k_{rad} (P_{rad,2} - P_{rad,1})$$

Variable	Symbol (Flow/Heat)	Free Molecular Flow Name (Unit)	Radiative Heat Transfer Name (Unit)
Flux	Q_{FM} / Q_{rad}	Throughput (pa-m ³ /sec)	Heat Flux (Watts/m ²)
Driving Force	P_{rad} / T^4	Pressure (Pa)	Temperature (K ⁴)
Constant	C / k_{rad}	Conductance (m ³ /sec)	Radiative Conductivity (Watts/m ² /K ⁴)





Models

Free Molecular Flow

- **Using the radiation heat transfer analogy, models are set up models in two manners**
 - **Fix the inlet and outlet boundaries identically, and make inlet flow areas identical in both chambers**
 - Look at system throughput
 - A higher value means a higher conductance
 - **Fix the outlet boundaries identically, make the inlet flow areas the same, and change the inlet boundary so the same system throughput is seen in both chambers**
 - Look at the driving force (pressure difference)
 - A smaller driving force means a higher conductance





Models

Free Molecular Flow

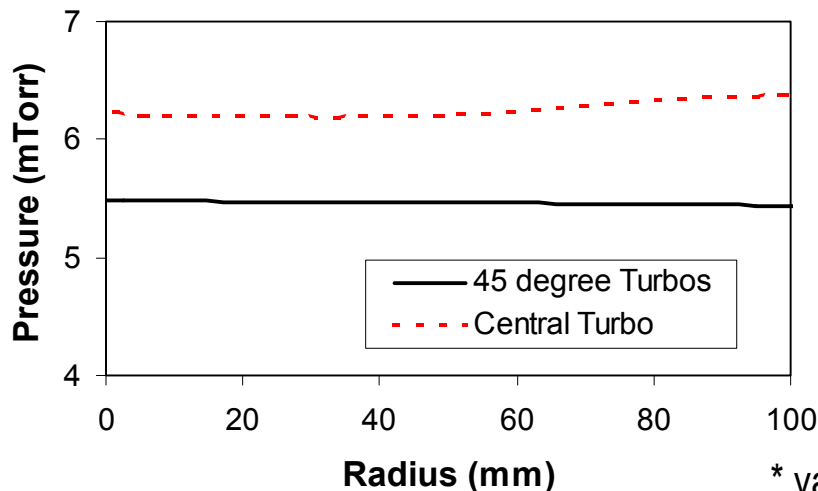
- **Inlets and outlets are modeled as isothermal boundaries with emissivity of one**
 - **Inlet and outlet temperatures chosen so local $Kn \geq 100$**
 - Local Kn (Knudsen number) is defined as the mean free path compared to a length scale based on local density gradients
- **All other walls are modeled as adiabatic walls with emissivity of zero per Peterson (1986)**
- **There is no direct comparison between this approach and transition flow models**
 - **They have widely different operating conditions**
 - **Good for relative comparisons**



Results

Transition Flow Models

- This model approximates the STI operating condition in pressure and volume flow rate (600 SCCM argon, no chemistry or deposition)
- We look at processing conditions (i.e. pressure) over the wafer (conductance changes with pressure)



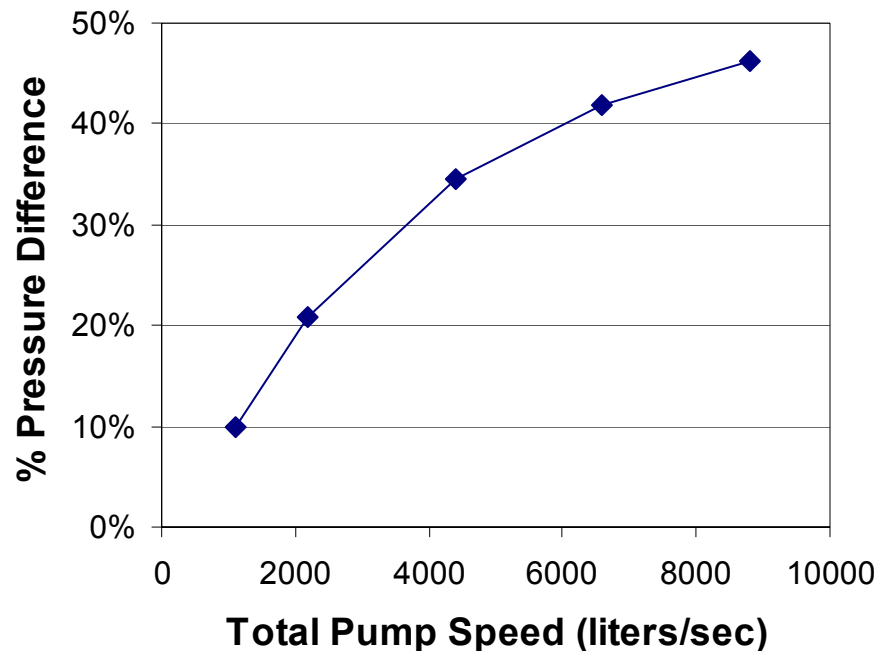
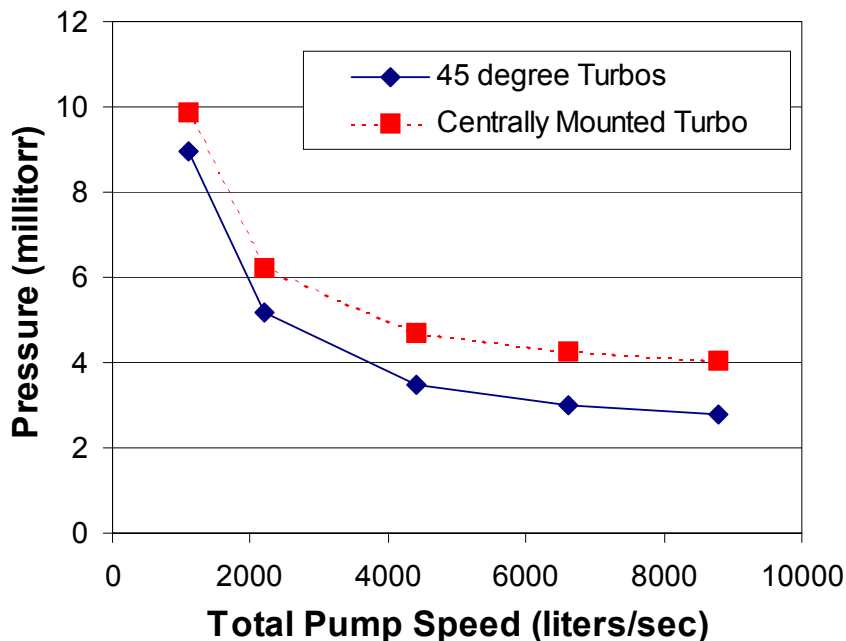
*Pressure over the wafer is 20% lower with the **Novellus SPEED™** design (two 1100 l/s turbos at 45°)

* van Schravendijk, et al., SEMI Conference (1999)

Results

Transition Flow Models

- **Models were also run for various pumping speeds**
 - **Pressure at wafer center 10-46% lower for 45° turbo design for pump speeds between 1100 and 8800 liters/sec**





Results

Free Molecular Flow Models

- **Both boundary condition set-ups the same results**
 - **Free molecular flow models provide a single conductance value for each design**
 - **Transition flow models have variable conductances as operating conditions change**

Summary of Results		
Performance Improvement with 45° Turbopumps	Transition Flow Models (pressure gain over wafer)	Free Molecular Flow Models (conductance gain)
% Gain	10-46%	24%

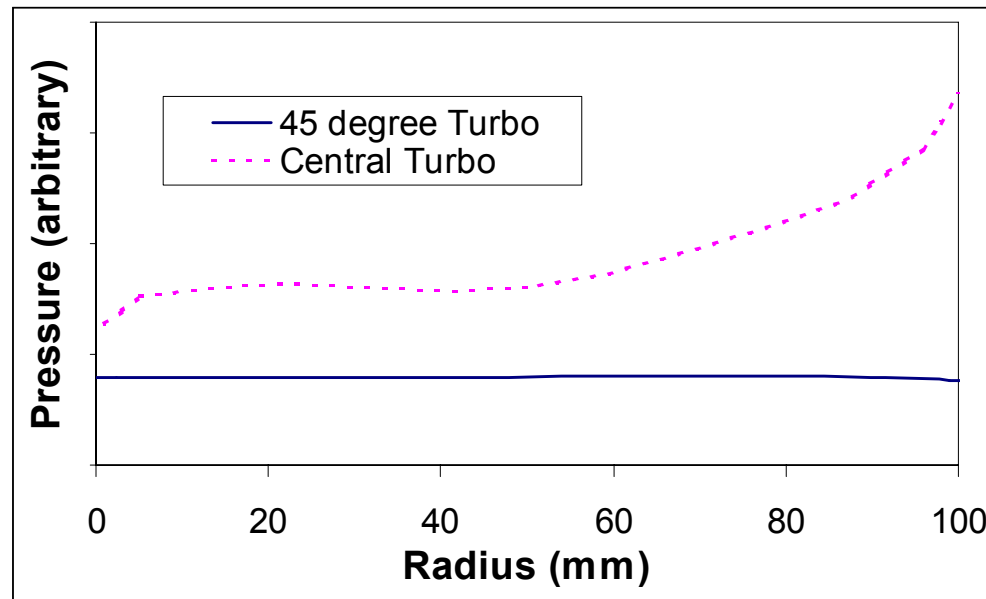




Results

Free Molecular Flow Models

- Using a “radiative pressure” equal to T^4 , we examine pressure over the wafer in free molecular flow
 - Direct correlation between “radiative pressure” and actual chamber wall pressures is not clear





Conclusions

- **Models were run in 3D for realistic semiconductor processing vacuum chambers**
 - Transition flow using Navier-Stokes with slip BCs
 - Free molecular flow using analogy to radiation heat transfer (Discrete Ordinates Method)
- **The *Novellus SPEED™* design with two turbopumps at 45° performs better than competing designs**
 - Competing design has a single centrally mounted turbo
 - Transition flow models show 10-46% lower pressure at wafer center with constant pump speeds in both systems
 - Free molecular flow conductance is 24% higher





Conclusions

- **Both modeling approaches show the same design trends and qualitative improvement levels**
 - **Only one model per design need be run using the free molecular flow approach**
 - **The radiation heat transfer analogy allows the user to model free molecular flow without Monte Carlo methods within commercial codes already in widespread use**
 - **Complex 3D geometries can be modeled easily**
 - **Such models can be used to quickly optimize conductance in chamber designs early in the development stage**





The Complete Copper Damascene Solution



TFUG/PEUG Meeting on Semiconductor Equipment and Process Modeling, Dec. 10, 2003